■ELECTRICAL CHARACTERISTICS ($Ta=-20\sim+75^\circ C$)

Item	Symbol	Test Conditions		min	typ*	max	Unit
Input voltage	V_{IH}			2.0	—	—	V
	V_{IL}	Data inputs		—	—	0.7	V
		G, Output control inputs		—	—	0.8	
Output voltage	V_{OH}	$V_{CC}=4.75V$, $V_{IH}=2V$, $V_{IL}=V_{IL\ max}$, $I_{OH}=-2.6mA$		2.4	—	—	V
	V_{OL}	$V_{CC}=4.75V$, $V_{IH}=2V$, $V_{IL}=V_{IL\ max}$	$I_{OL}=12mA$	—	—	0.4	V
			$I_{OL}=24mA$	—	—	0.5	
Off-state output current	I_{OZH}	$V_{CC}=5.25V$, $V_{IH}=2V$	$V_O=2.7V$	—	—	20	μA
	I_{OZL}		$V_O=0.4V$	—	—	−20	
Input current	I_{IH}	$V_{CC}=5.25V$, $V_I=2.7V$		—	—	20	μA
	I_{IL}	$V_{CC}=5.25V$, $V_I=0.4V$		—	—	−0.4	mA
	I_I	$V_{CC}=5.25V$, $V_I=7V$		—	—	0.1	mA
Short-circuit output current	I_{OS}	$V_{CC}=5.25V$		−30	—	−130	mA
Supply current	I_{CC}	$V_{CC}=5.25V$, $V_I=4.5V$ (Output control)		—	24	40	mA
Input clamp voltage	V_{IK}	$V_{CC}=4.75V$, $I_{IN}=-18mA$		—	—	−1.5	V

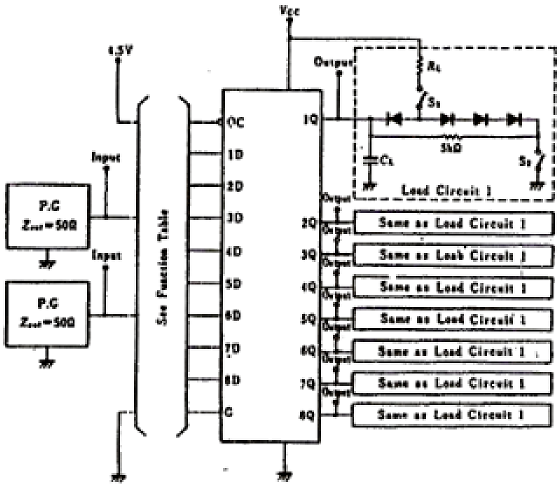
* $V_{CC}=5V$, $Ta=25^\circ C$

■SWITCHING CHARACTERISTICS ($V_{CC}=5V$, $Ta=25^\circ C$)

Item	Symbol	Input	Output	Test Conditions	min	typ	max	Unit
Propagation delay time	t_{PLH}	D	Q	$C_L=45pF$ $R_L=667\Omega$	—	12	18	ns
	t_{PHL}				—	12	18	
	t_{PLH}	G	Q		—	20	30	
	t_{PHL}				—	18	30	
Output enable time	t_{ZH}	OC	Q		—	15	28	
	t_{ZL}				—	25	36	
Output disable time	t_{HZ}	OC	Q	$C_L=5pF$ $R_L=667\Omega$	—	12	20	
	t_{LZ}				—	15	25	

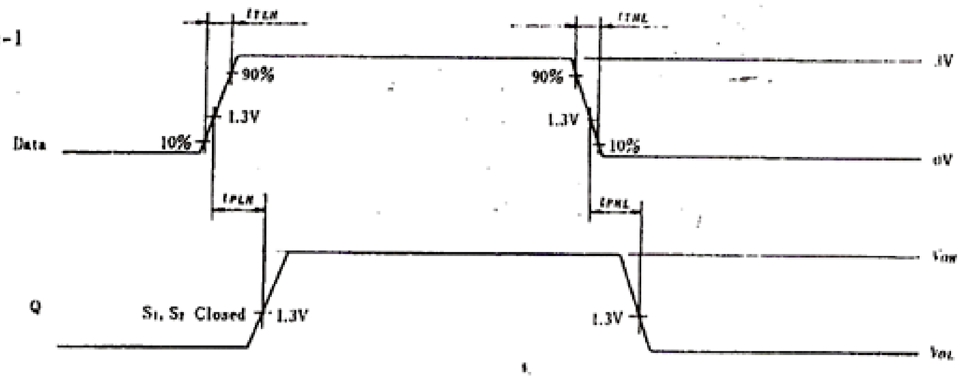
■TESTING METHOD

Test Circuit



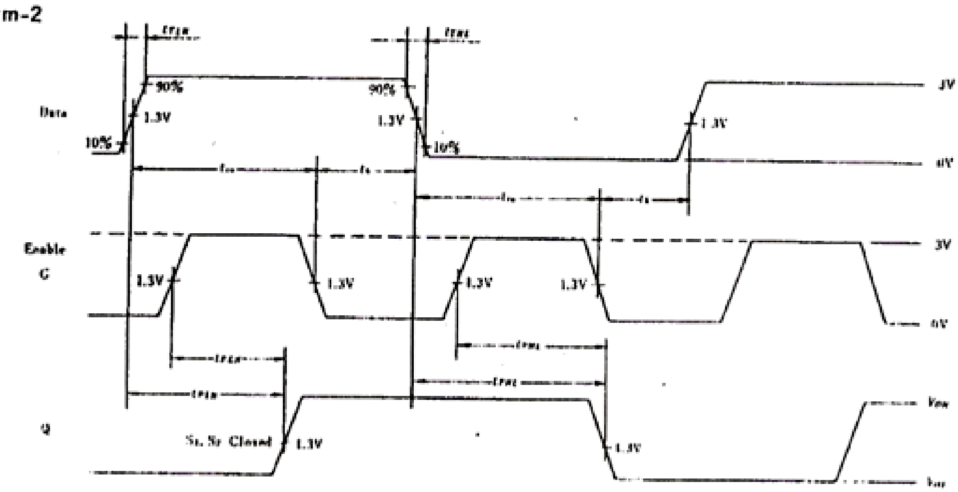
Notes:
1. C_L includes probe jig capacitance.
2. All diodes are 1S2074 Ⓗ.

Waveform-1



Notes: Input pulse; $t_{TLH} \leqq 15ns$, $t_{THL} \leqq 6ns$, $PRR = 1MHz$, duty cycle 50%

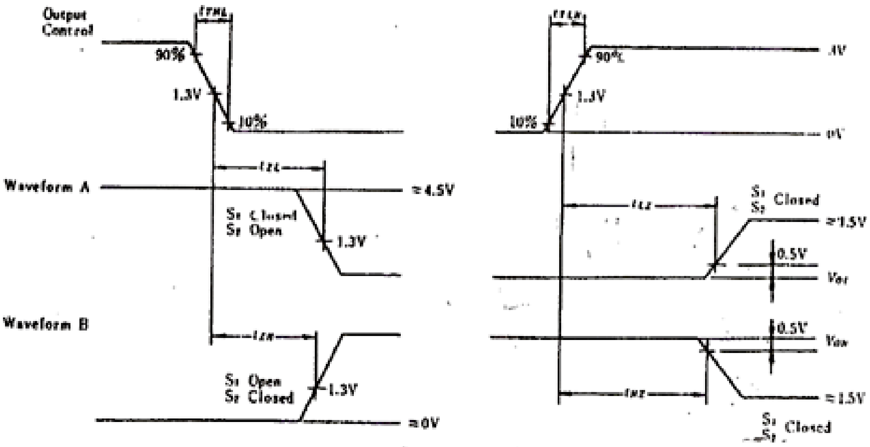
Waveform-2



Note: Enable input pulse; $t_{TLH} \leqq 15ns$, $t_{THL} \leqq 6ns$, $PRR = 1MHz$

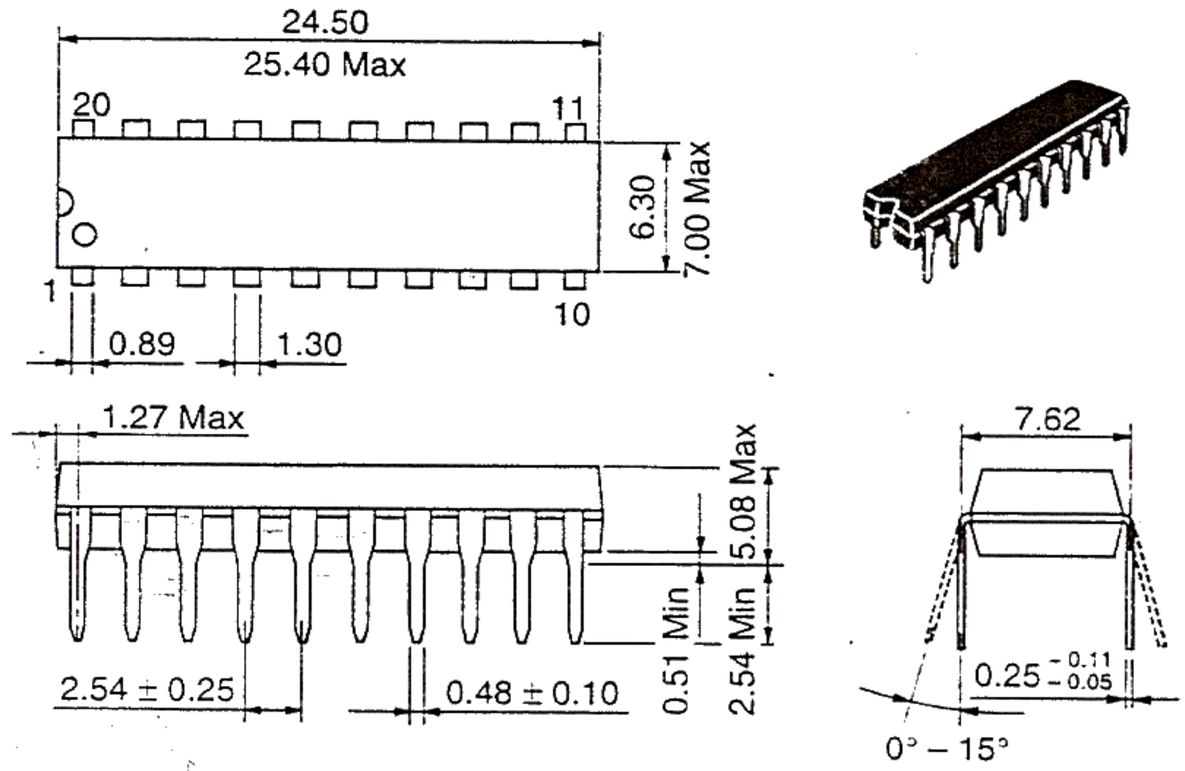
Data input pulse; $t_{TLH} \leqq 15ns$, $t_{THL} \leqq 6ns$, $PRR = 1MHz$, G input is high.

Waveform-3



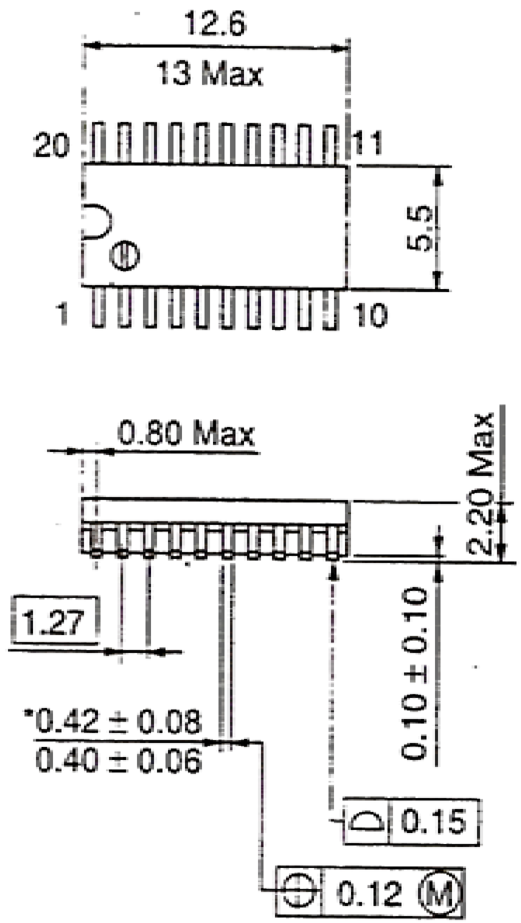
Notes:
1. Input pulse; $t_{TLH} \leqq 15ns$, $t_{THL} \leqq 6ns$, $PRR = 1MHz$, duty cycle 50%
2. Waveform A if for an output with internal conditions such that the output is low except when disabled by the output control. Waveform B is for an output with internal conditions such that the output is high except when disabled by the output control.

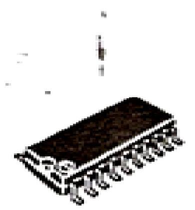
Unit: mm

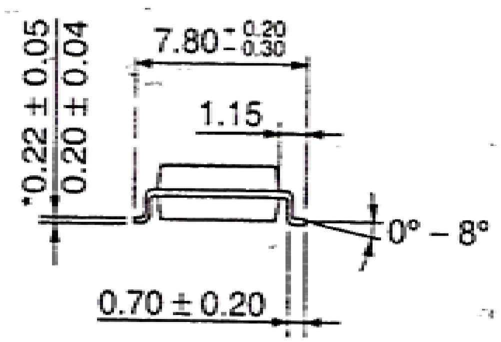


Hitachi Code	DP-20N
JEDEC	—
EIAJ	Conforms
Weight (reference value)	1.26 g

Unit: mm



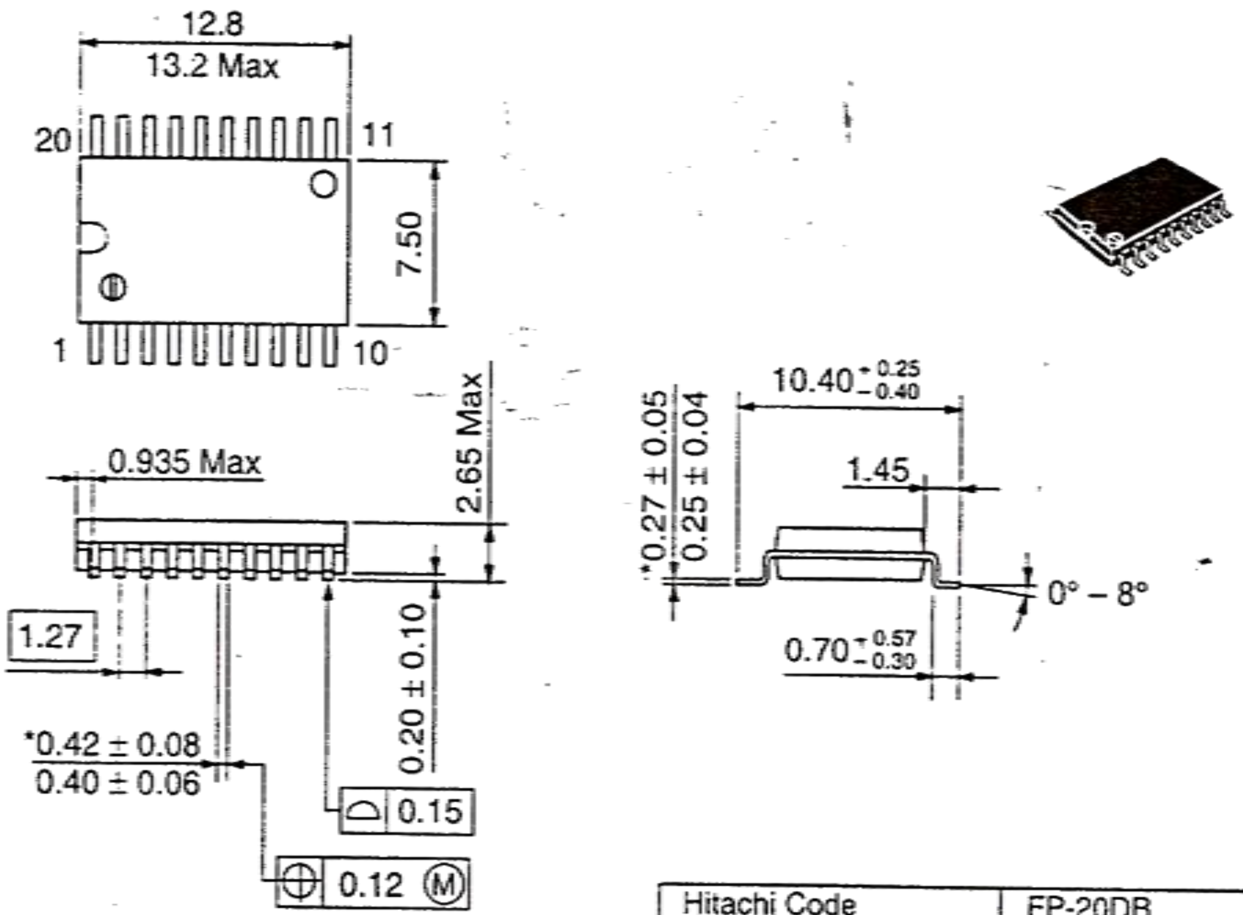




*Dimension including the plating thickness
Base material dimension

Hitachi Code	FP-20DA
JEDEC	—
EIAJ	Conforms
Weight (reference value)	0.31 g

Unit: mm



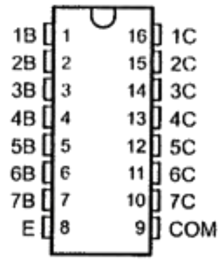
*Dimension including the plating thickness
Base material dimension

Hitachi Code	FP-20DB
JEDEC	Conforms
EIAJ	—
Weight (reference value)	0.52 g

The ULN2001A is obsolete and is no longer supplied.

- **500-mA-Rated Collector Current (Single Output)**
- **High-Voltage Outputs . . . 50 V**
- **Output Clamp Diodes**
- **Inputs Compatible With Various Types of Logic**
- **Relay-Driver Applications**

ULN2001A . . . D OR N PACKAGE
ULN2002A . . . N PACKAGE
ULN2003A . . . D, N, NS, OR PW PACKAGE
ULN2004A . . . D, N, OR NS PACKAGE
ULQ2003A, ULQ2004A . . . D OR N PACKAGE
(TOP VIEW)



description/ordering information

The ULN2001A, ULN2002A, ULN2003A, ULN2004A, ULQ2003A, and ULQ2004A are high-voltage, high-current Darlington transistor arrays. Each consists of seven npn Darlington pairs that feature high-voltage outputs with common-cathode clamp diodes for switching inductive loads. The collector-current rating of a single Darlington pair is 500 mA. The Darlington pairs can be paralleled for higher current capability. Applications include relay drivers, hammer drivers, lamp drivers, display drivers (LED and gas discharge), line drivers, and logic buffers. For 100-V (otherwise interchangeable) versions of the ULN2003A and ULN2004A, see the SN75468 and SN75469, respectively.

ORDERING INFORMATION

T_A	PACKAGE†		ORDERABLE PART NUMBER	TOP-SIDE MARKING
–20°C to 70°C	PDIP (N)	Tube of 25	ULN2002AN	ULN2002AN
			ULN2003AN	ULN2003AN
			ULN2004AN	ULN2004AN
	SOIC (D)	Tube of 40	ULN2003AD	ULN2003A
		Reel of 2500	ULN2003ADR	
		Tube of 40	ULN2004AD	ULN2004A
		Reel of 2500	ULN2004ADR	
	SOP (NS)	Reel of 2000	ULN2003ANSR	ULN2003A
			ULN2004ANSR	ULN2004A
	TSSOP (PW)	Tube of 90	ULN2003APW	UN2003A
		Reel of 2000	ULN2003APWR	
–40°C to 85°C	PDIP (N)	Tube of 25	ULQ2003AN	ULQ2003A
			ULQ2004AN	ULQ2004AN
	SOIC (D)	Tube of 40	ULQ2003AD	ULQ2003A
		Reel of 2500	ULQ2003ADR	ULQ2003A
		Tube of 40	ULQ2004AD	ULQ2004A
		Reel of 2500	ULQ2004ADR	ULQ2004A

† Package drawings, standard packing quantities, thermal data, symbolization, and PCB design guidelines are available at www.ti.com/sc/package.

Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

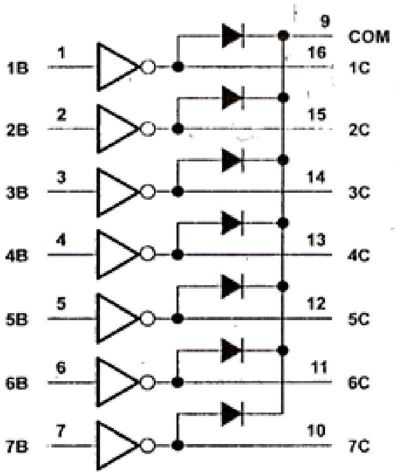
TEXAS INSTRUMENTS
POST OFFICE BOX 655303 • DALLAS, TEXAS 75265

The ULN2001A is obsolete and is no longer supplied.

description/ordering information (continued)

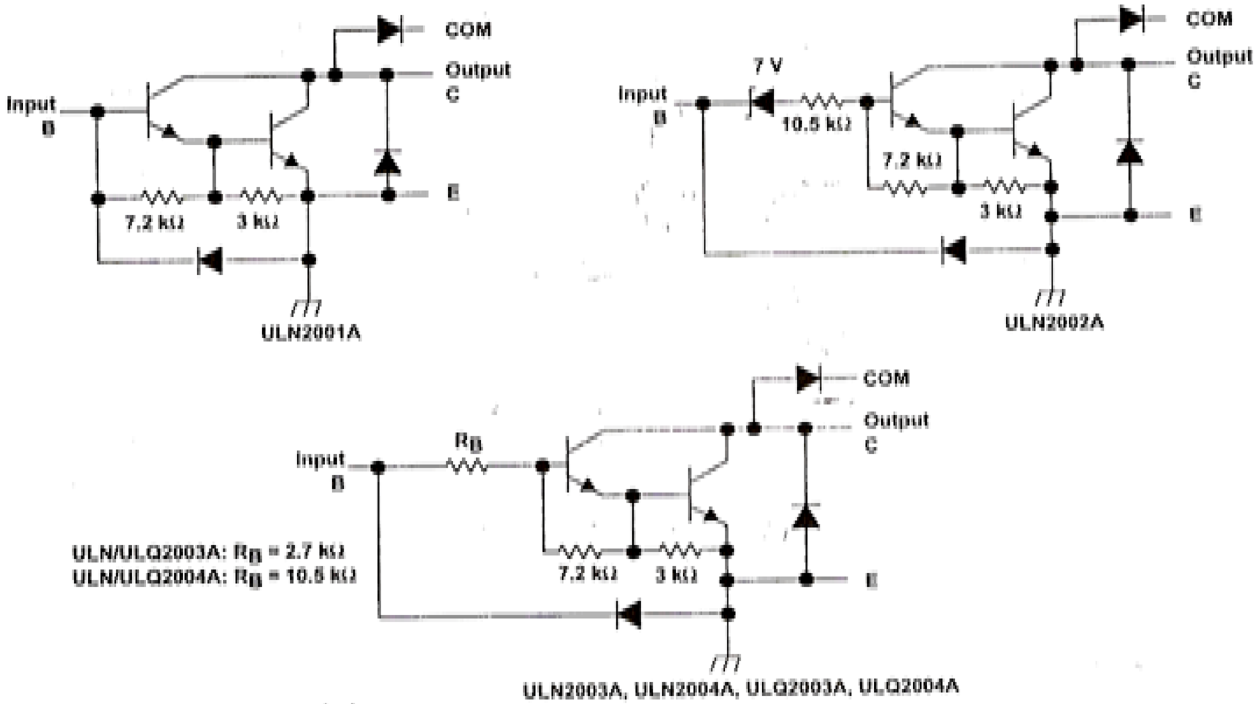
The ULN2001A is a general-purpose array and can be used with TTL and CMOS technologies. The ULN2002A is designed specifically for use with 14-V to 25-V PMOS devices. Each input of this device has a Zener diode and resistor in series to control the input current to a safe limit. The ULN2003A and ULQ2003A have a 2.7-kΩ series base resistor for each Darlington pair for operation directly with TTL or 5-V CMOS devices. The ULN2004A and ULQ2004A have a 10.5-kΩ series base resistor to allow operation directly from CMOS devices that use supply voltages of 6 V to 15 V. The required input current of the ULN/ULQ2004A is below that of the ULN/ULQ2003A, and the required voltage is less than that required by the ULN2002A.

logic diagram



The ULN2001A is obsolete
and is no longer supplied.

schematics (each Darlington pair)



All resistor values shown are nominal.

The ULN2001A is obsolete and is no longer supplied.

absolute maximum ratings at 25°C free-air temperature (unless otherwise noted)†

Collector-emitter voltage	50 V
Clamp diode reverse voltage (see Note 1)	50 V
Input voltage, V_I (see Note 1)	30 V
Peak collector current (see Figures 14 and 15)	500 mA
Output clamp current, I_{OK}	500 mA
Total emitter-terminal current	−2.5 A
Operating free-air temperature range, T_A, ULN200xA	−20°C to 70°C
ULQ200xA	−40°C to 85°C
ULQ200xAT	−40°C to 105°C
Package thermal impedance, θ_{JA} (see Notes 2 and 3): D package	73°C/W
N package	67°C/W
NS package	64°C/W
PW package	108°C/W
Package thermal impedance, θ_{JC} (see Notes 4 and 5): D package	36°C/W
N package	54°C/W
Operating virtual junction temperature, T_J	150°C
Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds	260°C
Storage temperature range, T_{stg}	−65°C to 150°C

† Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES:
1. All voltage values are with respect to the emitter/substrate terminal E, unless otherwise noted.
2. Maximum power dissipation is a function of T_J(max), θ_{JA}, and T_A. The maximum allowable power dissipation at any allowable ambient temperature is $P_D = (T_J(max) - T_A)/\theta_{JA}$. Operating at the absolute maximum T_J of 150°C can affect reliability.
3. The package thermal impedance is calculated in accordance with JESD 51-7.
4. Maximum power dissipation is a function of T_J(max), θ_{JC}, and T_C. The maximum allowable power dissipation at any allowable case temperature is $P_D = (T_J(max) - T_C)/\theta_{JC}$. Operating at the absolute maximum T_J of 150°C can affect reliability.
5. The package thermal impedance is calculated in accordance with MIL-STD-883.

electrical characteristics, T_A = 25°C (unless otherwise noted)

PARAMETER		TEST FIGURE	TEST CONDITIONS		ULN2001A MIN	ULN2001A TYP	ULN2001A MAX	ULN2002A MIN	ULN2002A TYP	ULN2002A MAX	UNIT
$V_{I(on)}$	On-state input voltage	6	V_{CE} = 2 V,	I_C = 300 mA						13	V
$V_{CE(sat)}$	Collector-emitter saturation voltage	5	I_I = 250 μA,	I_C = 100 mA		0.9	1.1		0.9	1.1	V
			I_I = 350 μA,	I_C = 200 mA		1	1.3		1	1.3	
			I_I = 500 μA,	I_C = 350 mA		1.2	1.6		1.2	1.6	
V_F	Clamp forward voltage	8	I_F = 350 mA			1.7	2		1.7	2	V
I_{CEX}	Collector cutoff current	1	V_{CE} = 50 V,	I_I = 0			50			50	μA
		2	V_{CE} = 50 V, T_A = 70°C	I_I = 0			100			100	
				V_I = 6 V						500	
$I_{I(off)}$	Off-state input current	3	V_{CE} = 50 V, T_A = 70°C	I_C = 500 μA,	50	65		50	65		μA
I_I	Input current	4	V_I = 17 V						0.82	1.25	mA
I_R	Clamp reverse current	7	V_R = 50 V,	T_A = 70°C			100			100	μA
			V_R = 50 V				50			50	
h_{FE}	Static forward-current transfer ratio	5	V_{CE} = 2 V,	I_C = 350 mA	1000						
C_i	Input capacitance		V_I = 0,	f = 1 MHz		15	25		15	25	pF

The ULN2001A is obsolete and is no longer supplied.

electrical characteristics, T_A = 25°C (unless otherwise noted) (continued)

PARAMETER		TEST FIGURE	TEST CONDITIONS		ULN2003A MIN	ULN2003A TYP	ULN2003A MAX	ULN2004A MIN	ULN2004A TYP	ULN2004A MAX	UNIT
$V_{I(on)}$	On-state input voltage	6	V_{CE} = 2 V	I_C = 125 mA						5	V
				I_C = 200 mA			2.4			6	
				I_C = 250 mA			2.7				
				I_C = 275 mA						7	
				I_C = 300 mA			3				
				I_C = 350 mA						8	
$V_{CE(sat)}$	Collector-emitter saturation voltage	5	I_I = 250 µA,	I_C = 100 mA		0.9	1.1		0.9	1.1	V
			I_I = 350 µA,	I_C = 200 mA		1	1.3		1	1.3	
			I_I = 500 µA,	I_C = 350 mA		1.2	1.6		1.2	1.6	
I_{CEX}	Collector cutoff current	1	V_{CE} = 50 V,	I_I = 0			50			50	µA
		2	V_{CE} = 50 V, T_A = 70°C	I_I = 0			100			100	
				V_I = 1 V						500	
V_F	Clamp forward voltage	8	I_F = 350 mA			1.7	2		1.7	2	V
$I_{I(off)}$	Off-state input current	3	V_{CE} = 50 V, T_A = 70°C	I_C = 500 µA,	50	65		50	65		µA
I_I	Input current	4	V_I = 3.85 V			0.93	1.35				mA
			V_I = 5 V						0.35	0.5	
			V_I = 12 V						1	1.45	
I_R	Clamp reverse current	7	V_R = 50 V				50			50	µA
			V_R = 50 V,	T_A = 70°C			100			100	
C_I	Input capacitance		V_I = 0,	f = 1 MHz		15	25		15	25	pF

The ULN2001A is obsolete and is no longer supplied.

PARAMETER MEASUREMENT INFORMATION

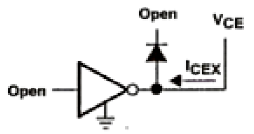


Figure 1. I_{CEX} Test Circuit

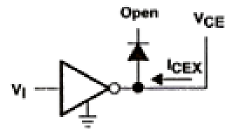


Figure 2. I_{CEX} Test Circuit

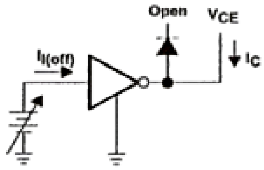


Figure 3. $I_{I(off)}$ Test Circuit

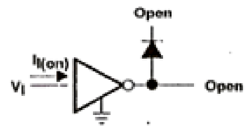
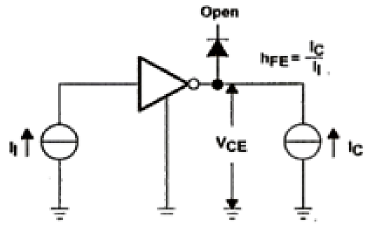


Figure 4. I_I Test Circuit



NOTE: I_I is fixed for measuring $V_{CE(sat)}$, variable for measuring h_{FE}.

Figure 5. h_{FE}, $V_{CE(sat)}$ Test Circuit

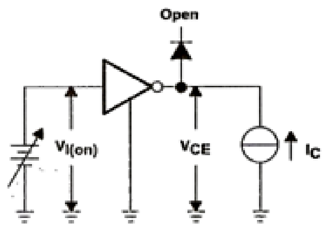


Figure 6. $V_{I(on)}$ Test Circuit

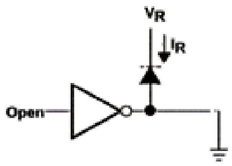


Figure 7. I_R Test Circuit

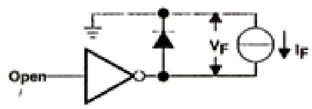


Figure 8. V_F Test Circuit

The ULN2001A is obsolete and is no longer supplied.

electrical characteristics over recommended operating conditions (unless otherwise noted)

PARAMETER		TEST FIGURE	TEST CONDITIONS		ULQ2003A MIN	ULQ2003A TYP	ULQ2003A MAX	ULQ2004A MIN	ULQ2004A TYP	ULQ2004A MAX	UNIT
$V_{I(on)}$	On-state input voltage	6	V_{CE} = 2 V	I_C = 125 mA						5	V
				I_C = 200 mA			2.7			6	
				I_C = 250 mA			2.9				
				I_C = 275 mA						7	
				I_C = 300 mA			3				
				I_C = 350 mA						8	
$V_{CE(sat)}$	Collector-emitter saturation voltage	5	I_I = 250 μA,	I_C = 100 mA		0.9	1.2		0.9	1.1	V
			I_I = 350 μA,	I_C = 200 mA		1	1.4		1	1.3	
			I_I = 500 μA,	I_C = 350 mA		1.2	1.7		1.2	1.6	
I_{CEX}	Collector cutoff current	1	V_{CE} = 50 V,	I_I = 0			100			50	μA
		2	V_{CE} = 50 V	I_I = 0						100	
				V_I = 1 V						500	
V_F	Clamp forward voltage	8	I_F = 350 mA			1.7	2.3		1.7	2	V
$I_{I(off)}$	Off-state input current	3	V_{CE} = 50 V,	I_C = 500 μA		65		50	65		μA
I_I	Input current	4	V_I = 3.85 V			0.93	1.35				mA
			V_I = 5 V						0.35	0.5	
			V_I = 12 V						1	1.45	
I_R	Clamp reverse current	7	V_R = 50 V,	T_A = 25°C			100			50	μA
			V_R = 50 V				100			100	
C_I	Input capacitance		V_I = 0,	f = 1 MHz		15	25		15	25	pF

switching characteristics, T_A = 25°C

PARAMETER		TEST CONDITIONS		ULN2001A, ULN2002A, ULN2003A, ULN2004A MIN	TYP	MAX	UNIT
t_{PLH}	Propagation delay time, low- to high-level output	See Figure 9			0.25	1	μs
t_{PHL}	Propagation delay time, high- to low-level output	See Figure 9			0.25	1	μs
V_{OH}	High-level output voltage after switching	V_S = 50 V, See Figure 10	I_O ≈ 300 mA,	V_S−20			mV

switching characteristics over recommended operating conditions (unless otherwise noted)

PARAMETER		TEST CONDITIONS		ULQ2003A, ULQ2004A MIN	TYP	MAX	UNIT
t_{PLH}	Propagation delay time, low- to high-level output	See Figure 9			1	10	μs
t_{PHL}	Propagation delay time, high- to low-level output	See Figure 9			1	10	μs
V_{OH}	High-level output voltage after switching	V_S = 50 V, See Figure 10	I_O ≈ 300 mA,	V_S−500			mV

The ULN2001A is obsolete and is no longer supplied.

PARAMETER MEASUREMENT INFORMATION

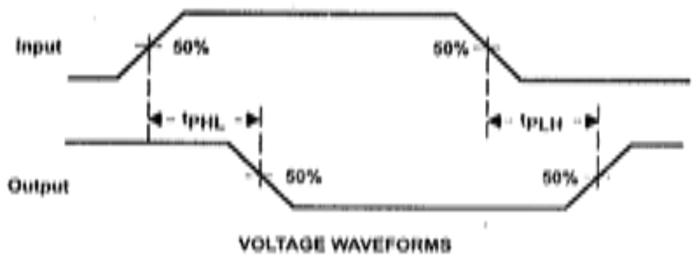
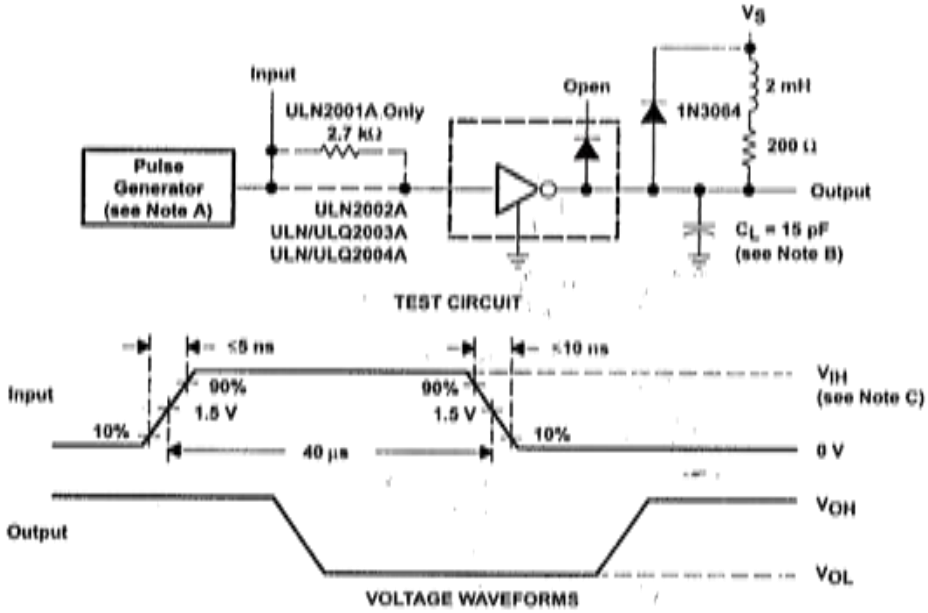


Figure 9. Propagation Delay-Time Waveforms



NOTES: A. The pulse generator has the following characteristics: PRR = 12.5 kHz, Z_O = 50 Ω.
B. C_L includes probe and jig capacitance.
C. For testing the ULN2001A, the ULN2003A, and the ULQ2003A, V_{IH} = 3 V; for the ULN2002A, V_{IH} = 13 V; for the ULN2004A and the ULQ2004A, V_{IH} = 8 V.

Figure 10. Latch-Up Test Circuit and Voltage Waveforms

The ULN2001A is obsolete
and is no longer supplied.

TYPICAL CHARACTERISTICS

COLLECTOR-EMITTER
SATURATION VOLTAGE
vs
COLLECTOR CURRENT
(ONE DARLINGTON)

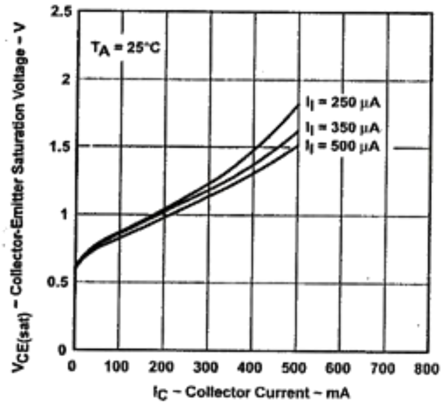


Figure 11

COLLECTOR-EMITTER
SATURATION VOLTAGE
vs
TOTAL COLLECTOR CURRENT
(TWO DARLINGTONS IN PARALLEL)

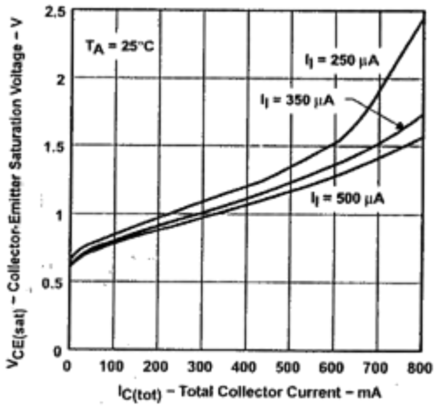


Figure 12

COLLECTOR CURRENT
vs
INPUT CURRENT

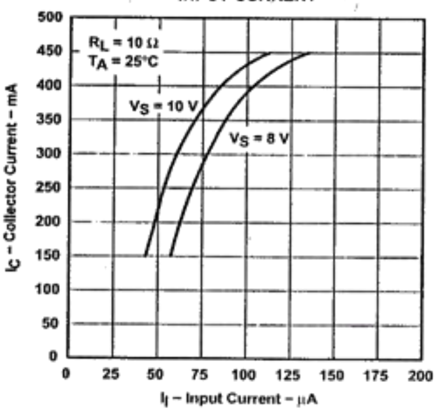


Figure 13

The ULN2001A is obsolete and is no longer supplied.

THERMAL INFORMATION

D PACKAGE
MAXIMUM COLLECTOR CURRENT
vs
DUTY CYCLE

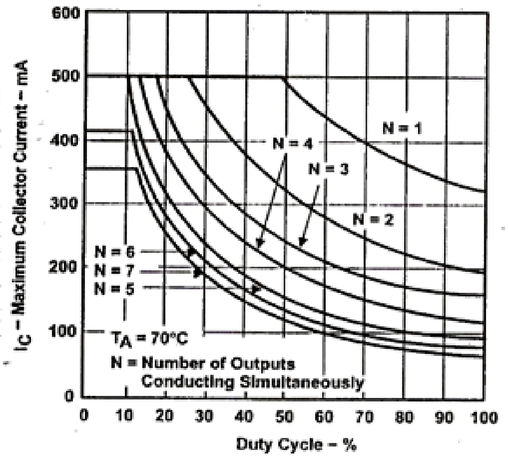


Figure 14

N PACKAGE
MAXIMUM COLLECTOR CURRENT
vs
DUTY CYCLE

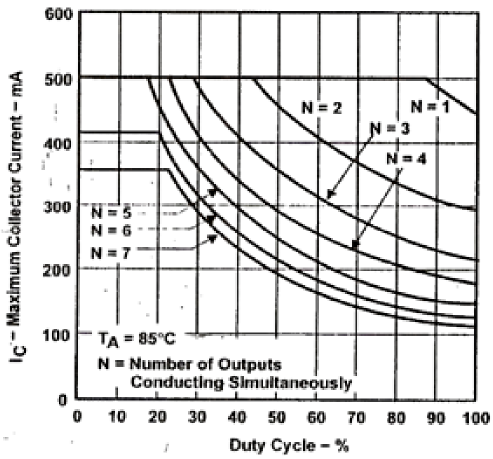


Figure 15

The ULN2001A is obsolete
and is no longer supplied.

APPLICATION INFORMATION

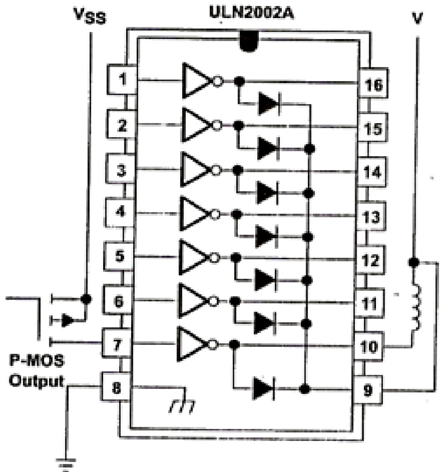


Figure 16. P-MOS to Load

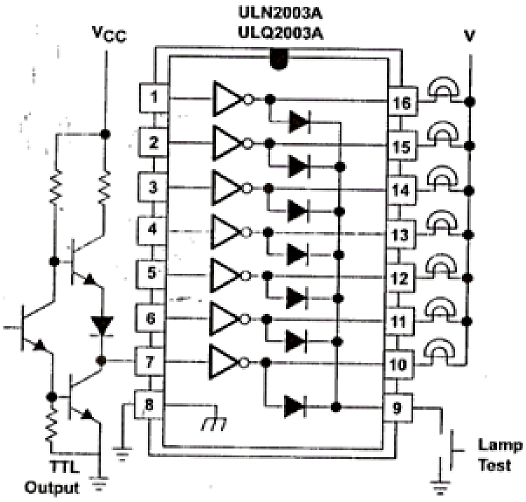


Figure 17. TTL to Load

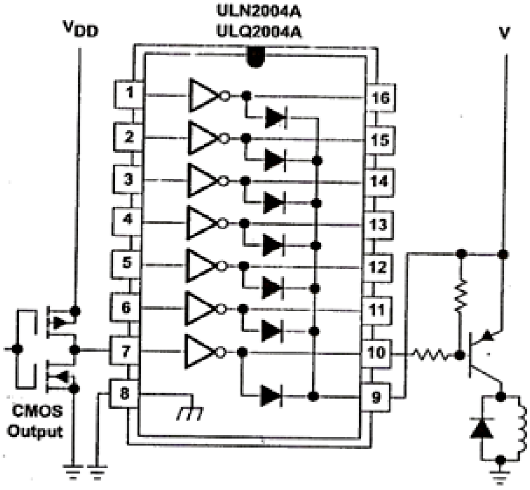


Figure 18. Buffer for Higher Current Loads

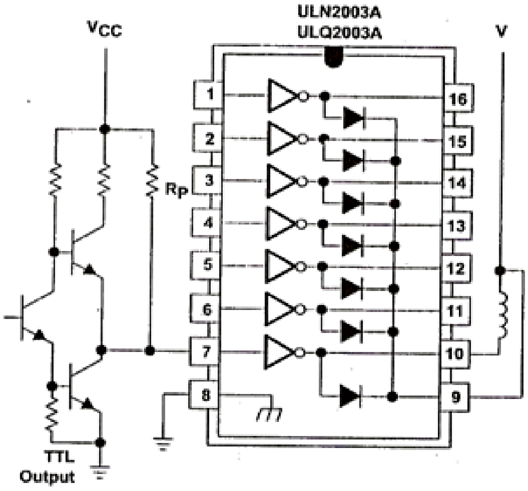


Figure 19. Use of Pullup Resistors to Increase Drive Current